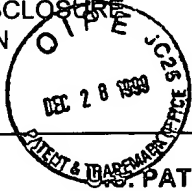


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Sheet 1 of 1

FORM PTO-1449  <b>INFORMATION DISCLOSURE CITATION</b>	ATTY. DOCKET NO. <div style="text-align: center;">7537.29</div>	SERIAL NO. <div style="text-align: center;">09/298,245</div>
	APPLICANTS <div style="text-align: center;">E. Excel International</div>	
	FILING DATE <div style="text-align: center;">April 23, 1999</div>	GROUP <div style="text-align: center;">1615</div>



## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<u>P</u> A1	5,834,044	11/10/98	Schmitz et al.	426	73	05/06/97
<u>P</u> A2	5,744,187	04/28/98	Gaynor	426	599	12/16/96
<u>P</u> A3	5,738,887	04/14/98	Wu	426	51	10/04/96
<u>P</u> A4	5,290,605	03/01/94	Shapira	424	439	10/18/92
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<u>P</u> A6	4,737,367	04/12/88	Langer et al.	426	72	07/26/85
<u>P</u> A7	4,732,773	03/22/88	Schott	426	590	07/11/83
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<u>P</u> A9	4,078,092	03/07/78	Nishiyama	426	584	08/24/76
A10						

## FOREIGN PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
A11						

## OTHER DOCUMENTS

(Including Author (if any), Title, Pertinent Pages, Date and Place of Publication)


*EXAMINER INITIAL	DOCUMENT CITATION
A12	

EXAMINER 	DATE CONSIDERED <div style="text-align: center;">8.24.00</div>
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Sheet 1 of 2

FORM PTO-1449	ATTY. DOCKET NO. 7537.29	SERIAL NO. 09/298,245
INFORMATION DISCLOSURE CITATION 	APPLICANTS Jau-Fei Chen	
	FILING DATE April 23, 1999	GROUP 1615

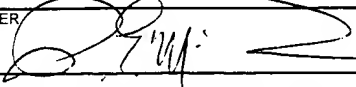
## U.S. PATENT DOCUMENTS

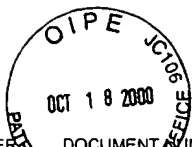
<del>CONFIDENTIAL</del>		<u>DOCUMENT NUMBER</u>	<u>DATE</u>	<u>NAME</u>	<u>CLASS</u>	<u>SUBCLASS</u>	<u>FILING DATE</u>
<u>*EXAMINER</u>	<u>INITIAL</u>						
<u>P</u>	A6	5,578,312	11/26/96	Parrinello	424	401	12/15/94
<u>      </u>	A7						
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<u>      </u>							

## FOREIGN PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<input checked="" type="checkbox"/>	W0 96 27383 A		PCT (French language document)			X
<input checked="" type="checkbox"/>	English abstract of Korean patent document No. 97 032 503 A		Korea			
<input checked="" type="checkbox"/>	English abstract of South African patent document No. ZA 6 000 062 A		South Africa			
<input checked="" type="checkbox"/>	English abstract of Japanese patent document No. 58 067151 A		Japan			
<input checked="" type="checkbox"/>	English abstract of Spanish patent document No. 2 041 218 B		Spain			
<input checked="" type="checkbox"/>	27 03 189 A		Germany			X
<input checked="" type="checkbox"/>	English abstract of Japanese patent document No. 09 249576 A		Japan			
<input checked="" type="checkbox"/>	English abstract of Japanese patent document No. 61 085324 A		Japan			
<input checked="" type="checkbox"/>	English abstract of Chinese patent document No. 1 076 624 A		China			
<input checked="" type="checkbox"/>	English abstract of Chinese patent document No. 1 090 988 A		China			

N/A  
2.2.01

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<u>R</u>	English abstract of Japanese patent document No. 63 116669 A		Japan				
<u>R</u>	English abstract of Japanese patent document No. 07 267,977 A		Japan				
<u>R</u>	English abstract of Chinese patent document No. 1,211 403 A		China				
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<u>R</u>	9 249576		Japan				X
<u>R</u>	61 85324		Japan				X
<u>R</u>	1076624 A		China				X
<u>R</u>	1090988 A		China				X
<u>R</u>	63 116669		Japan				X
<u>R</u>	7 267977		Japan				X
<u>R</u>	1211403 A		China				X
<u>R</u>	97 032 503A		Korea				X
<u>R</u>	English abstract of Japanese patent document No. 10072338		Japan				
<u>R</u>	2 041 218 B		Spain				X

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## OTHER DOCUMENTS

(Including Author (if any), Title, Pertinent Pages, Date and Place of Publication)

\*EXAMINER  
INITIAL

## DOCUMENT CITATION

- R PCT search report dated July 24, 2000 for PCT international application No. PCT/ US00/10168
- R PCT search report dated July 26, 2000 for PCT international application No. PCT/ US00/ 10112

EXAMINER <u>R</u>	DATE CONSIDERED 2.2.01
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